

EE 531: ADVANCED VLSI DESIGN

Floorplanning

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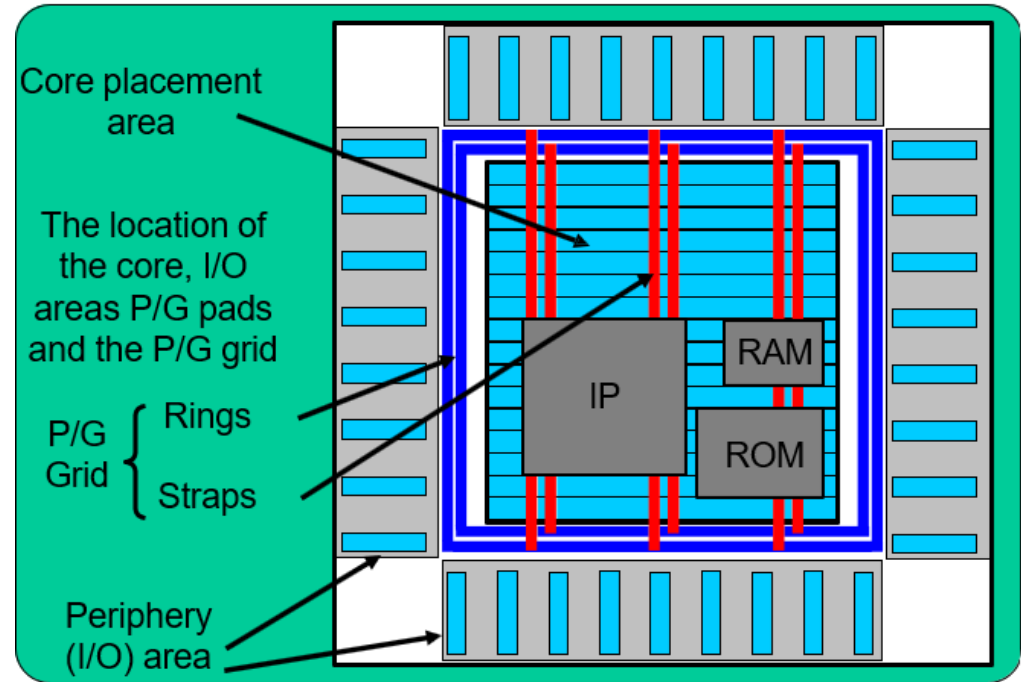
February, 2025

FLOORPLANNING GOALS AND OBJECTIVES

- **Floorplanning** is a mapping between the **logical description** (the **netlist**) and the **physical description** (the **floorplan**).
- **Goals of floorplanning:**
 - Arrange the blocks on a chip.
 - Decide the location of the I/O pads.
 - Decide the location and number of the power pads.
 - Decide the type of power distribution.
 - Decide the location and type of clock distribution.
- **Objectives of floorplanning:**
 - Minimize the chip area
 - Minimize delay
 - Minimize routing congestion

FULL CHIP DESIGN OVERVIEW

- Chip size
- Number of Gates
- Number of Metal layers
- Interface to the outside
- Hard IPs/Macros
- Power Delivery
- Multiple Voltages
- Clocking Scheme
- Flat or Hierarchical?



FLOORPLANNING INPUTS AND OUTPUTS

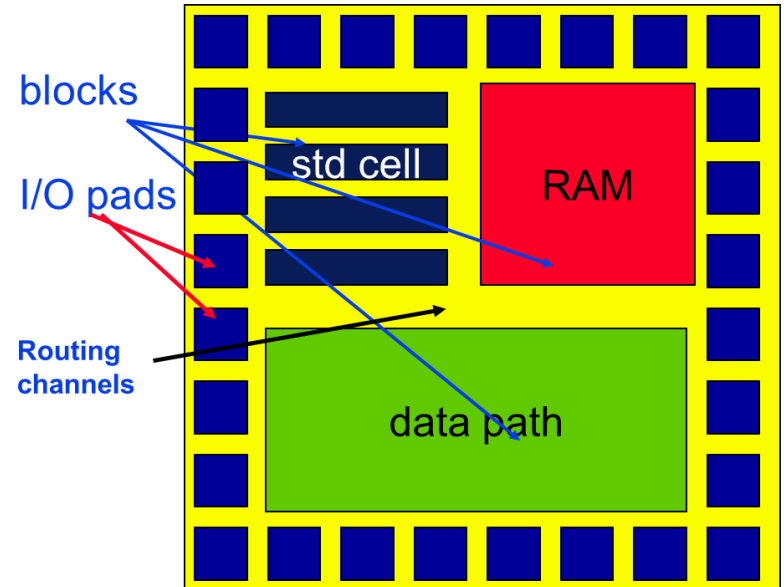
- **Inputs**

- Design netlist (required)
- Area requirements (required)
- Power requirements (required)
- Timing constraints (required)
- Physical partitioning information (required)
- Die size vs. performance vs. schedule trade-off (required)
- I/O placement (optional)
- Macro placement information (optional)

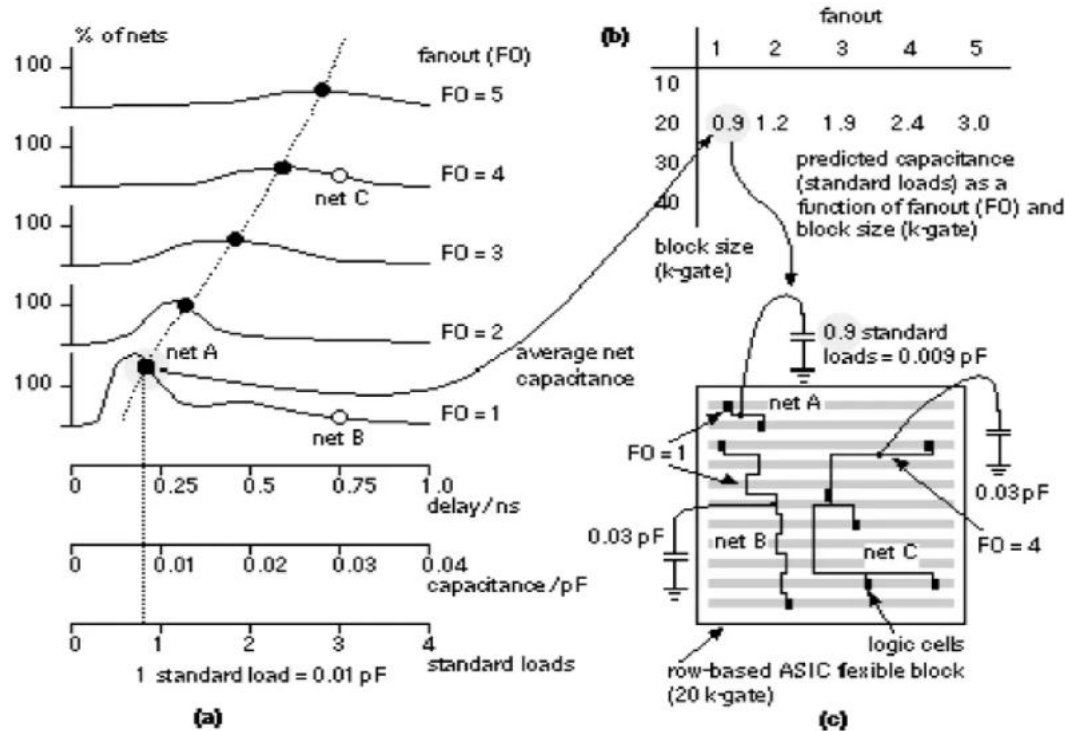
FLOORPLANNING INPUTS AND OUTPUTS

- **Outputs**

- Die/block area
 - I/Os placed
 - Macros placed
 - Power grid designed
 - Power pre-routing
 - Standard cell placement areas
- Design ready for standard cell placement



FLOORPLANNING: DELAY MEASUREMENT

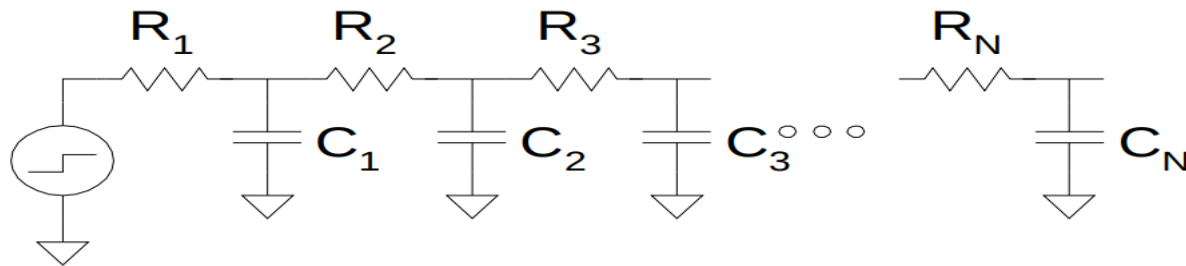


ELMORE DELAY

- Elmore delay of RC ladder

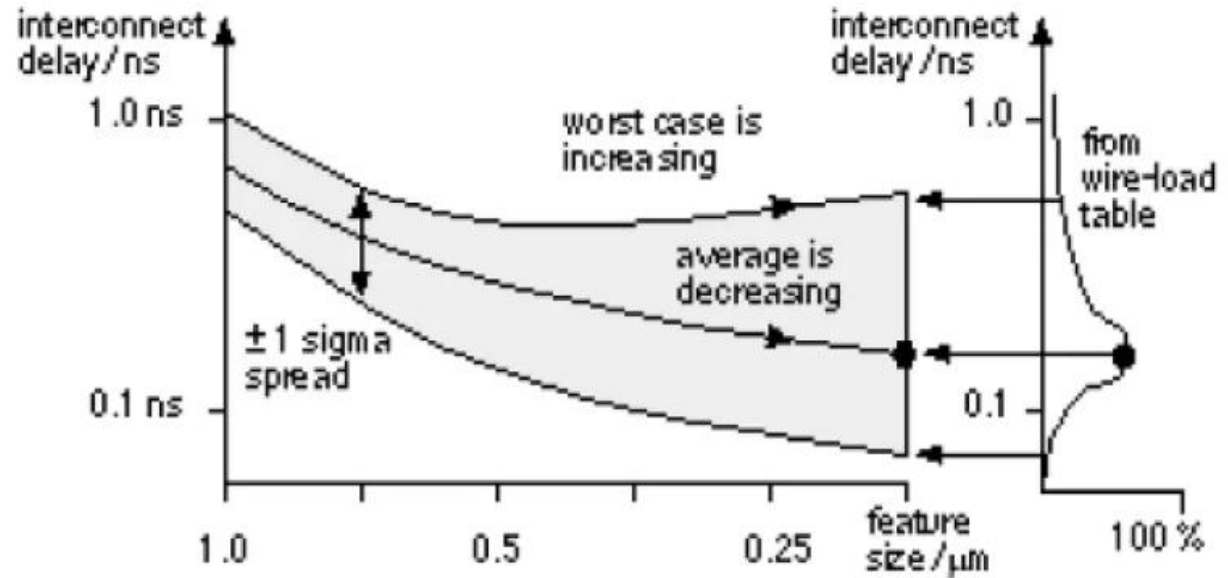
$$t_{pd} \approx \sum_{\text{nodes } i} R_{i-\text{to-source}} C_i$$

$$= R_1 C_1 + (R_1 + R_2) C_2 + \dots + (R_1 + R_2 + \dots + R_N) C_N$$

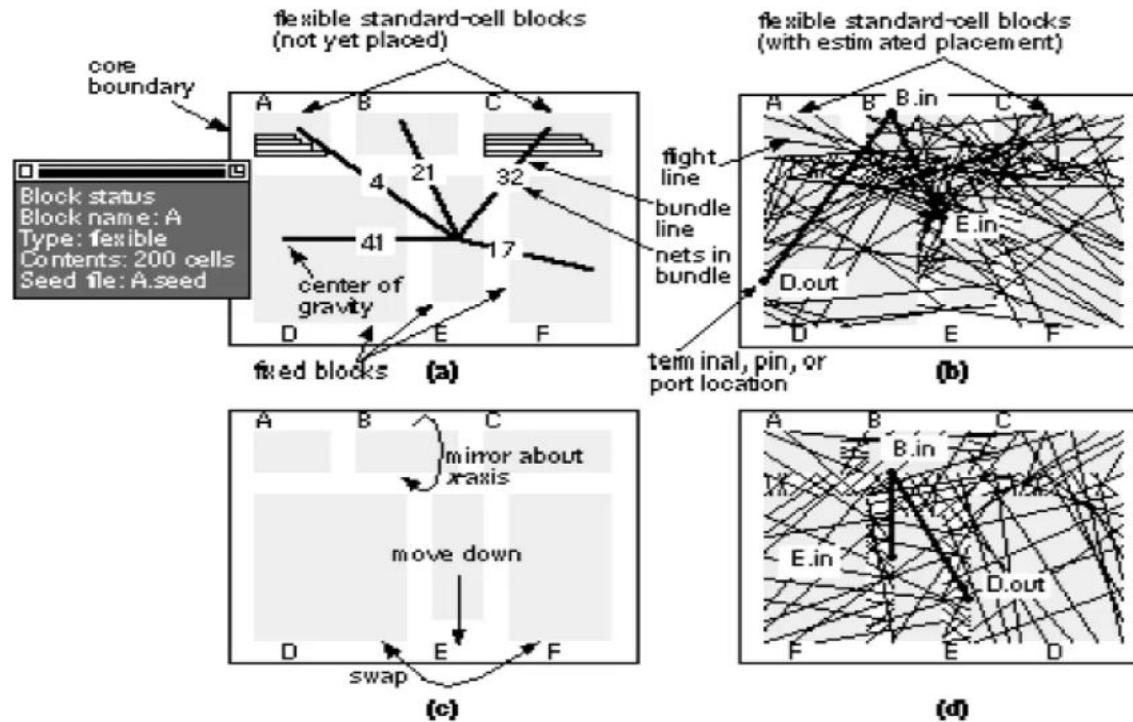


FLOORPLANNING: WORST CASE DELAY

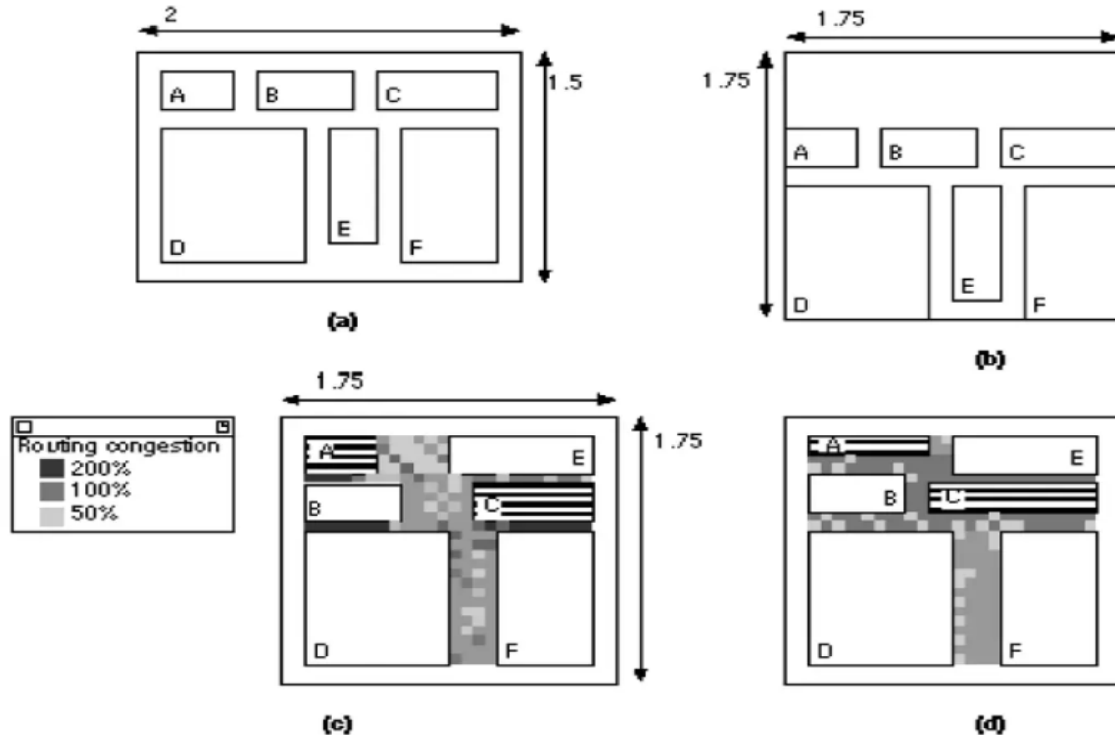
Worst-case interconnect delay. As we scale circuits, but avoid scaling the chip size, the worst-case interconnect delay increases.



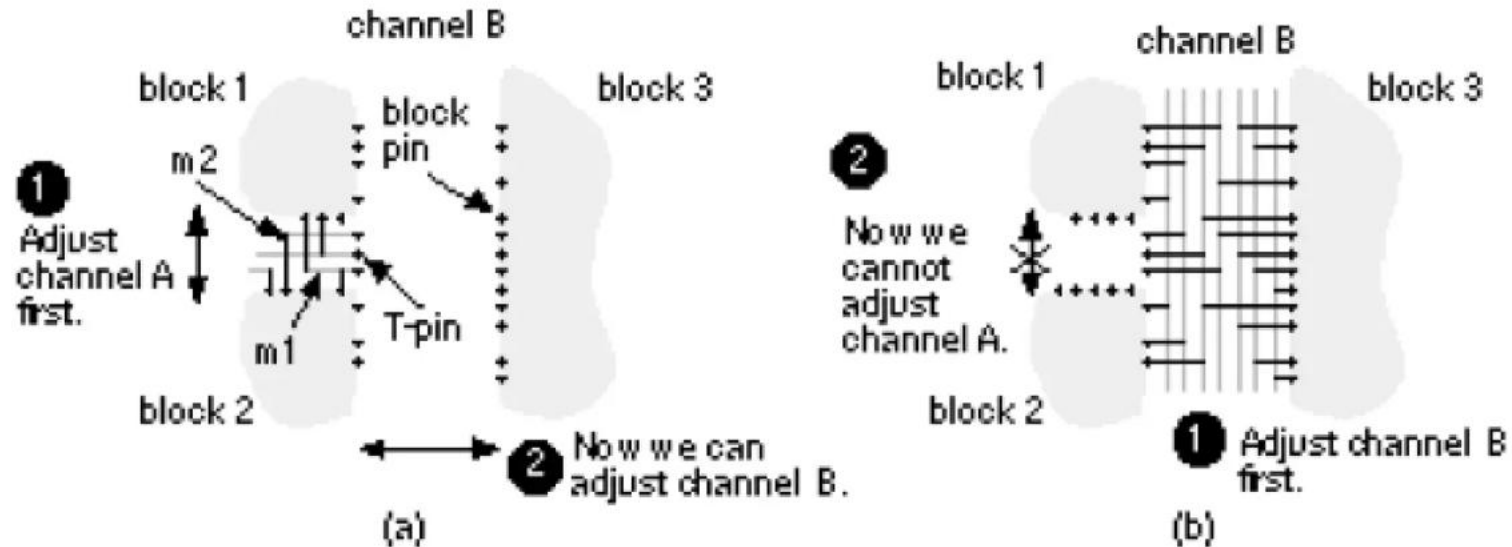
FLOORPLANNING TOOLS: OPTIMIZATION



FLOORPLANNING TOOLS: CONGESTION ANALYSIS



FLOORPLANNING TOOLS: CHANNEL DEFINITION

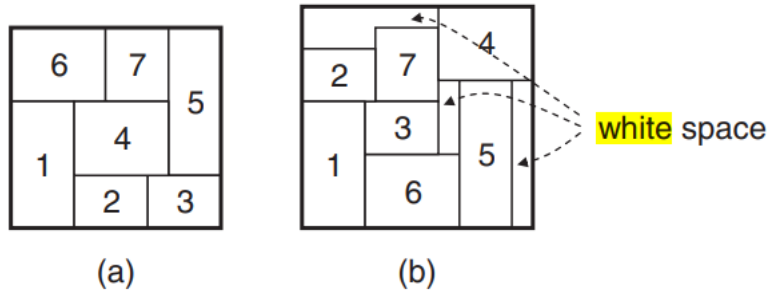


IMPORTANCE

- These decisions impact not only the functionality of the circuit, but also its performance.
- Mismanagement of channel allocation can lead to the following issues:
 - **Increased wiring congestion:** If one channel gets blocked or overused, it can force wires into longer paths, which increase the delay and may cause timing violations.
 - **Suboptimal area usage:** Poor routing can increase the area required for interconnects, leading to a larger chip size.
 - **Signal integrity issues:** Routing conflicts may also result in overlapping and congested wires which can lead to signal interference and other electrical problems.

FLOORPLANNING: WHITE SPACE MINIMIZATION

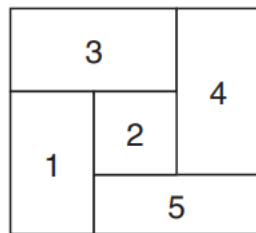
- The space in the floorplan bounding rectangle uncovered by any module is called white space or dead space



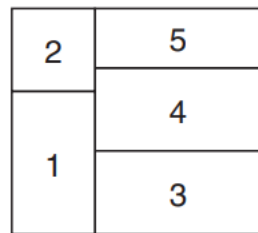
(a) an optimal floorplan in terms of area. (b) a non-optimal floorplan.

FLOORPLANNING MODELS

- We can classify floorplans into two categories for discussions:
 - **Slicing floorplans:** A slicing floorplan can be obtained by repetitively cutting the floorplan horizontally or vertically
 - **Non-slicing floorplans:** A non-slicing floorplan cannot be obtained by repetitively cutting the floorplan horizontally or vertically



(a)

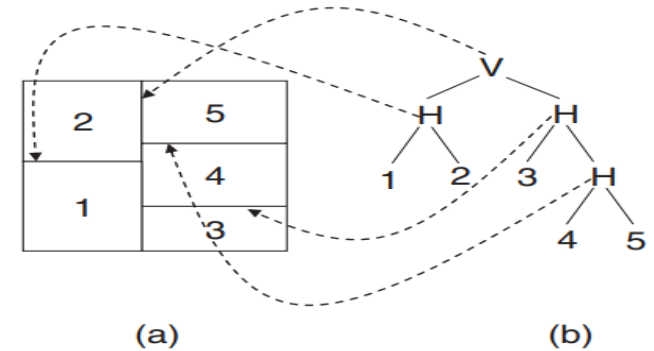


(b)

Examples of (a) a non-slicing floorplan. (b) a slicing floorplan.

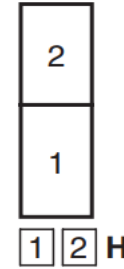
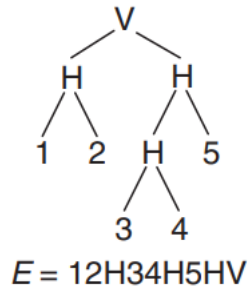
SLICING FLOORPLANS

- On the basis of the slicing property of a slicing floorplan, we can use a binary tree to represent a slicing floorplan [Otten 1982].
- A slicing tree is a binary tree with modules at the leaves and cut types at the internal nodes.
- There are two cut types, H and V.
- The H cut divides the floorplan horizontally, and the left (right) child represents the bottom (top) sub-floorplan.
- Similarly, the V cut divides the floorplan vertically, and the left (right) child represents the left (right) sub-floorplan.

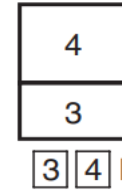


An example of (a) a slicing floorplan. (b) a slicing tree modeling.

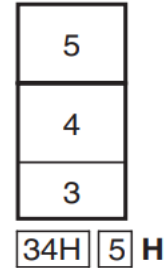
BINARY TREES AND POLISH EXPRESSIONS



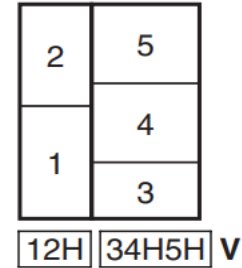
(a)



(b)

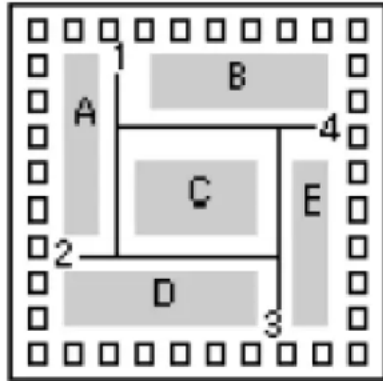


(c)

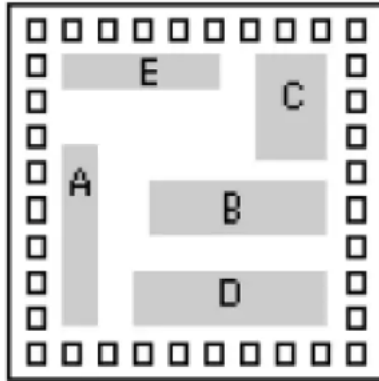


(d)

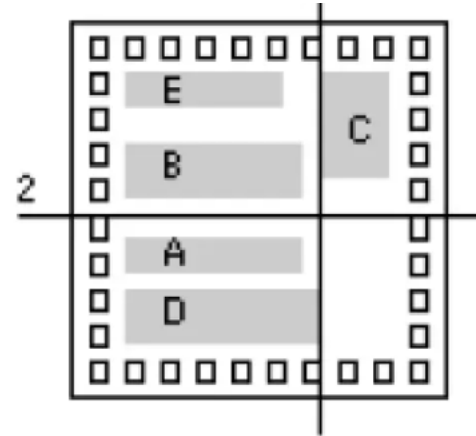
NON-SLICING FLOORPLANS



(a)



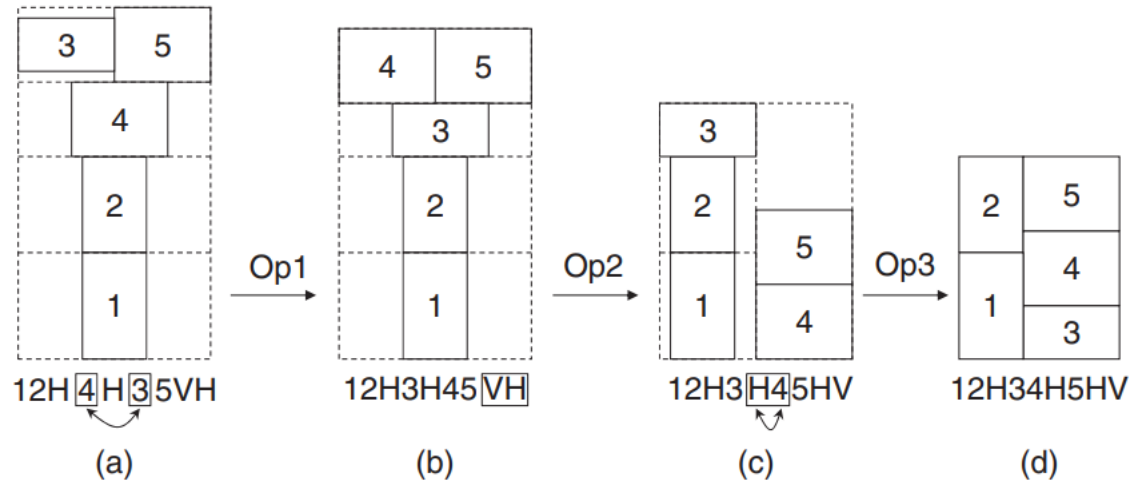
(b)



(c)

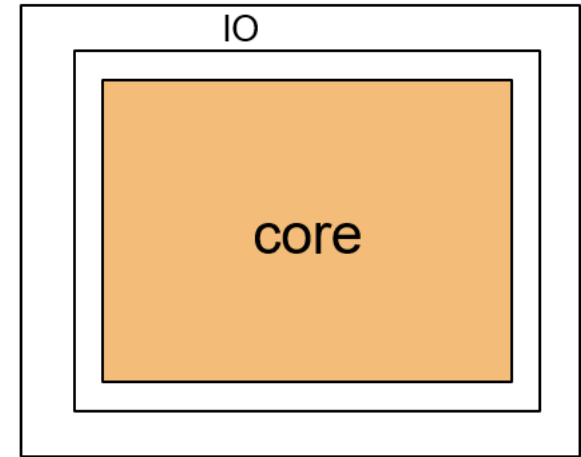
- Non-slicing blocks often lead to routing congestion
- Solution:
 - Move the blocks until we have a slicing floorplan
 - Use of L-shaped channels

NON-SLICING FLOORPLANS OPTIMIZATION

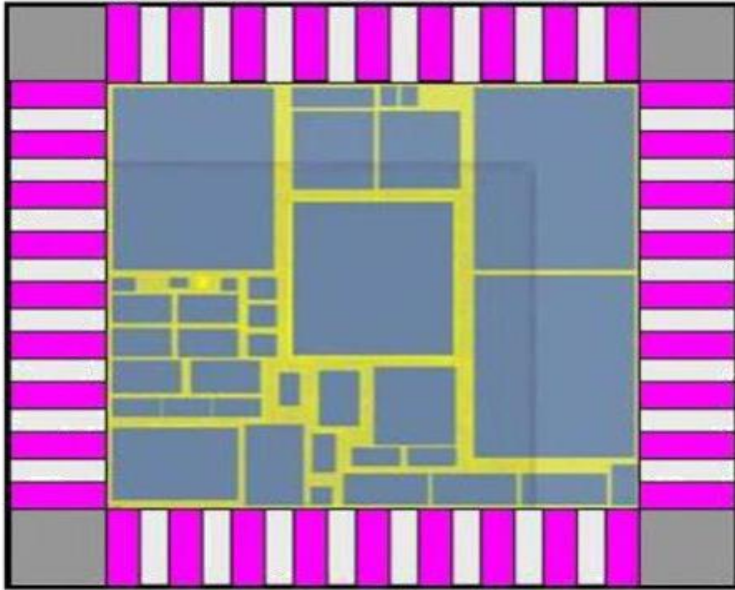


IO RING

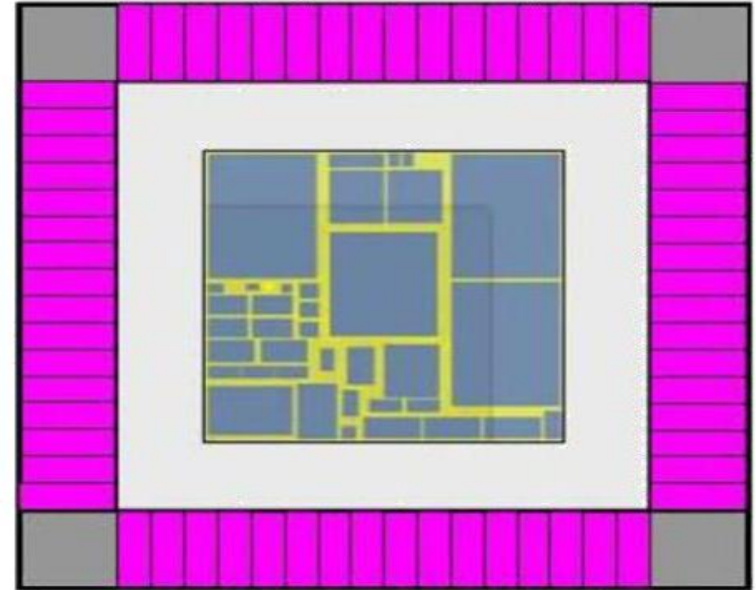
- **The pinout is often decided by front-end designers, with input from physical design and packaging engineers.**
 - I/Os do not tend to scale with Moore's Law and therefore, they are very expensive (in terms of area).
 - I/Os are not only needed for connecting signals to the outside world, but also to provide power to the chip.
 - Therefore, I/O planning is a critical and very central stage in Floorplanning the chip.



HOW DO WE CHOOSE OUR CHIP SIZE?



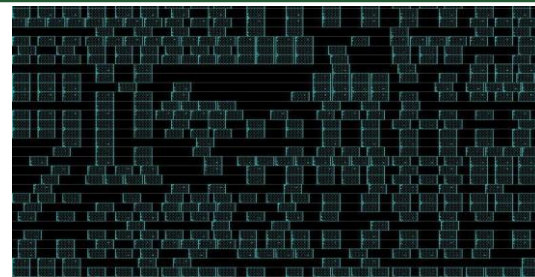
“Core Limited”



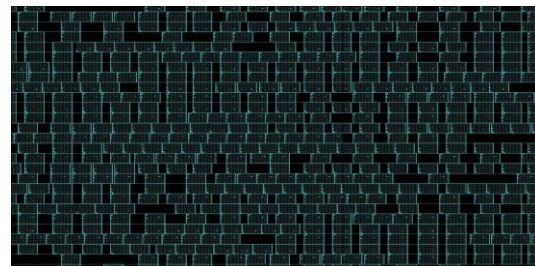
“Pad Limited”

UTILIZATION

- **Utilization** refers to the percentage of core area that is taken up by standard cells.
 - A typical starting utilization might be 70%
 - This can vary a lot depending on the design
- High utilization can make it difficult to close a design
 - Routing congestion
 - Negative impact during optimization legalization stages.
- Local congestion
 - Can occur with pin-dense cells like multiplexers, so utilization is not completely sufficient for determining die size.
 - Run a quick trial route to check for routing congestion
 - Refine the synthesis or increase routing resources



Low standard-cell
utilization



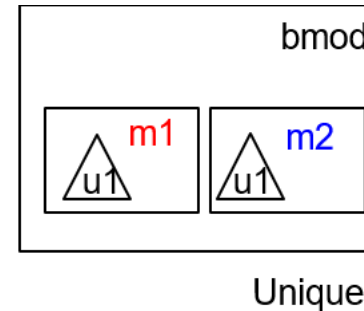
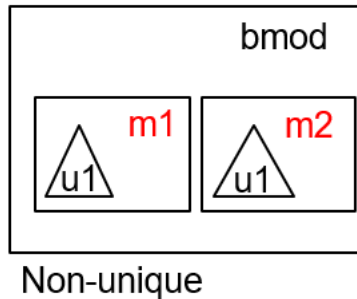
High standard-cell
utilization

UNIQUIFYING THE NETLIST

- When moving to the physical domain, the netlist must be **unique**
 - A unique netlist, means that each sub-module is only referenced once.
 - In the example, the non-unique netlist cannot optimize instance m1/u1 without changing instance m2/u1

```
module amod ();
  BUFFD1 u1 ();
endmodule

module bmod ();
  amod m1 ;
  amod m2 ;
endmodule
```



```
module amod1 ();
  BUFFD1 u1 ();
endmodule

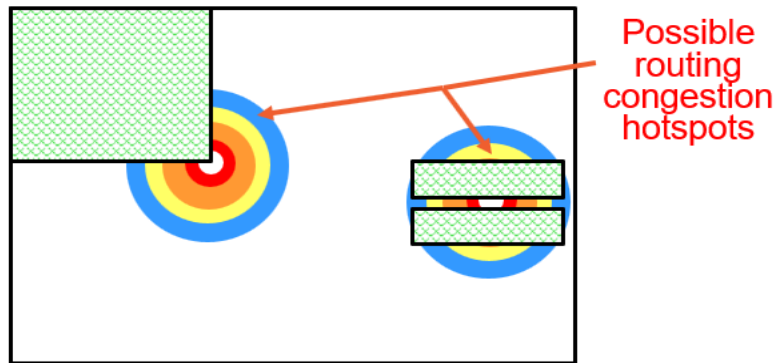
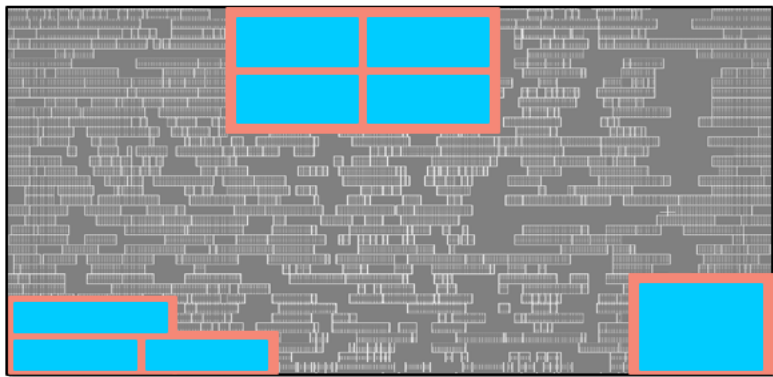
module amod2 ();
  BUFFD1 u1 ();
endmodule

module bmod ();
  amod1 m1 ;
  amod2 m2 ;
endmodule
```

- A synthesized netlist must be **uniquified** before placement can begin. This can be done either by the synthesizer or during design import.

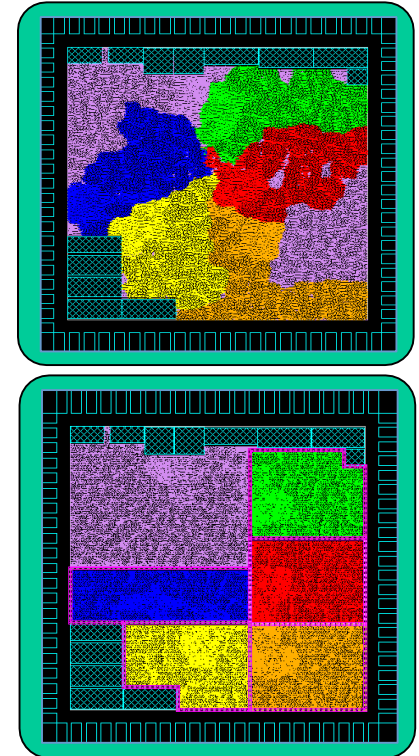
HARD MACRO PLACEMENT

- When placing large macros we must consider impacts on routing, timing and power.
- Usually **push them to the sides** of the floorplan.
 - Placement algorithms generally perform better with a single large rectangular placement area.
 - For wire-bond place power hungry macros away from the chip center.
- After placing hard macros, mark them as FIXED.



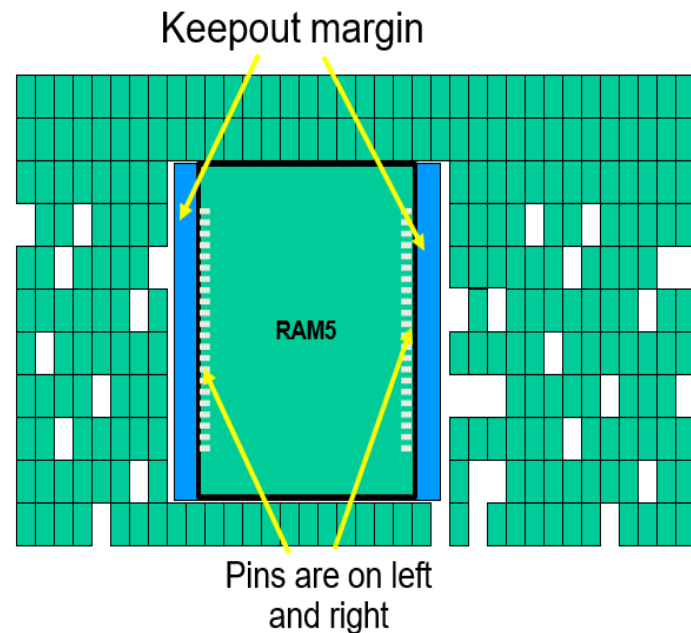
PLACEMENT REGIONS

- Sometimes, we want to “help” the tool put certain logic in certain regions or cluster them together.
- Place and Route tools define several types of placement regions:
 - **Soft guide** – try to cluster these cells together without a defined area.
 - **Guide** – try to place the cells in the defined area.
 - **Region** – must place the cells in the defined area, but other cells may also be placed there.
 - **Fence** – must place the cells in the defined area and keep out all other cells.

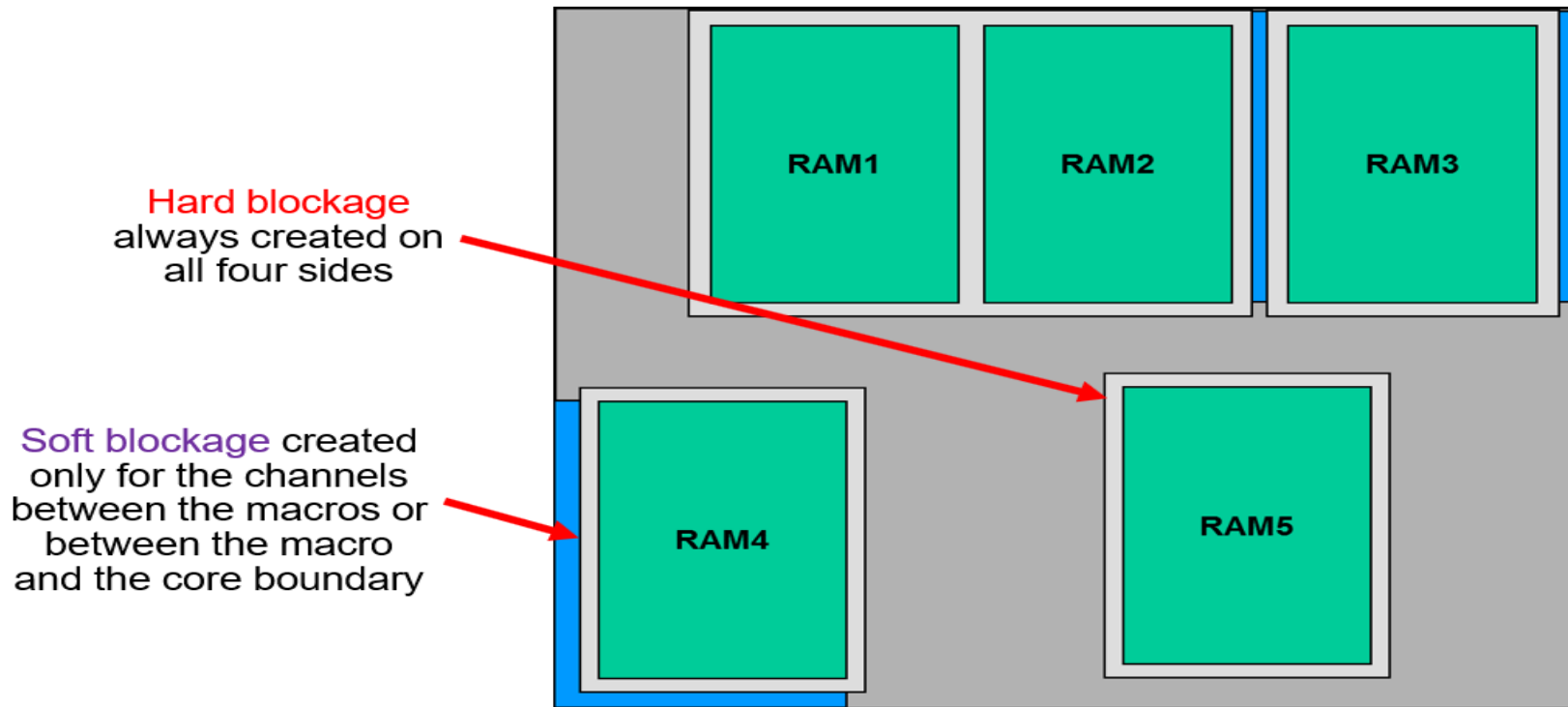


PLACEMENT BLOCKAGES AND HALOS

- Placement blockage halos are areas that the tools should not place any cells.
- These, too, have several types:
 - **Hard Blockage** – no cells can be placed inside.
 - **Soft Blockage** – cannot be used during placement, but may be used during optimization.
 - **Partial Blockage** – an area with lower utilization.
 - **Halo (padding)** – an area outside a macro that should be kept clear of standard cells.



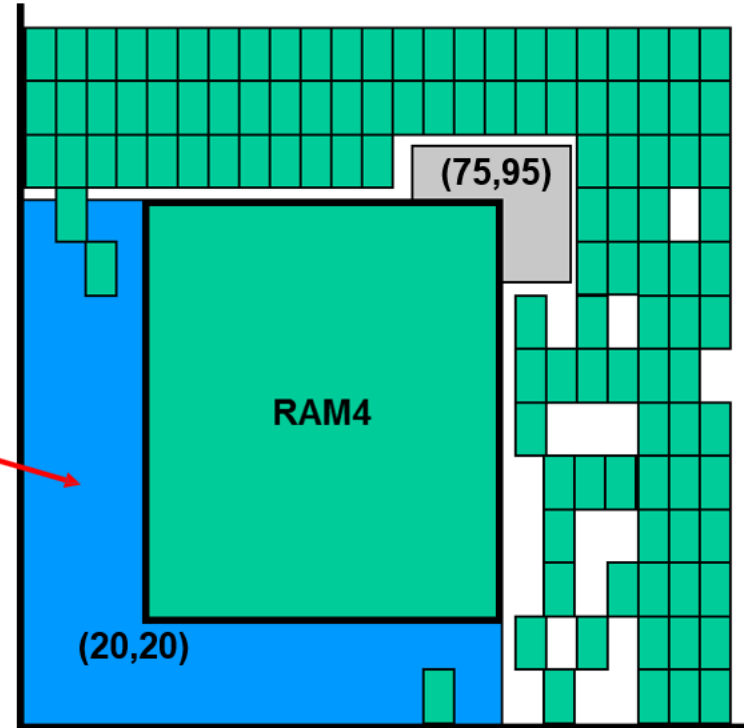
PLACEMENT BLOCKAGES AND HALOS



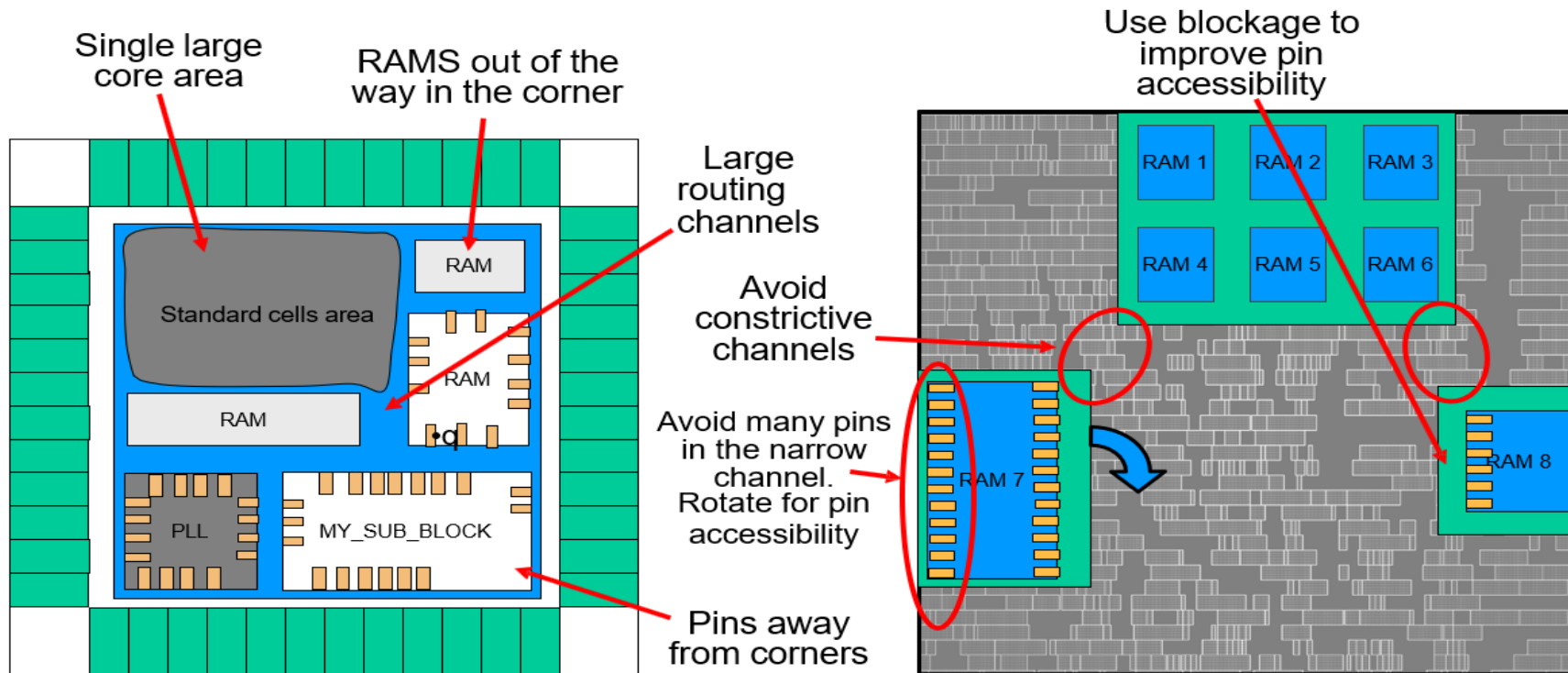
ROUTING BLOCKAGE

- Similar to placement blockage, **routing blockage** can be defined.
 - Blockage is defined for a given layer.

Routing
blockage



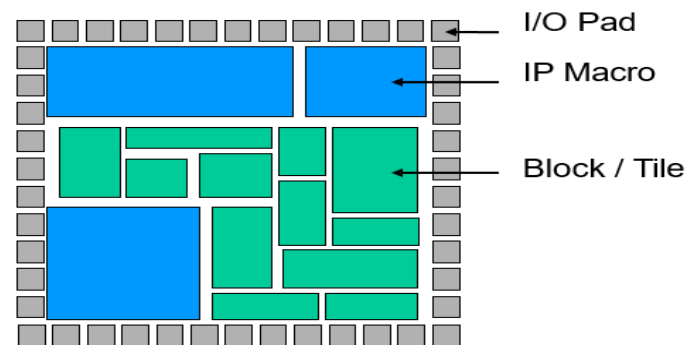
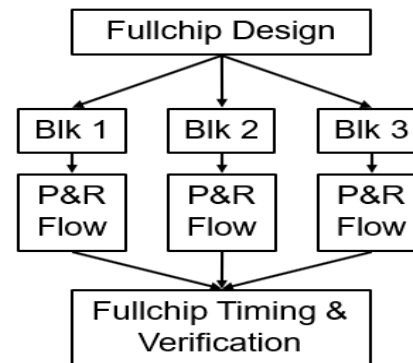
GUIDELINES FOR A GOOD FLOORPLAN



Hierarchical Design Concepts

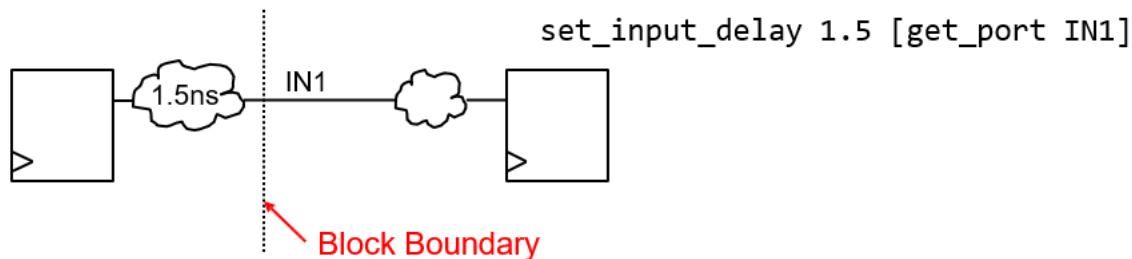
FLAT VS. HIERARCHICAL DESIGN

- If the design is too big, partition it into **hierarchies**
- **Advantages:**
 - Faster **runtime**, less memory needed for EDA tools
 - Faster **ECO** turn-around time
 - Ability to do design **re-use**
- **Disadvantages:**
 - Much more difficult for full-chip **timing closure** (ILMs)
 - More intensive **design planning** needed:
 - Feedthrough generation
 - Repeater insertion
 - Timing constraint budgeting
 - etc.

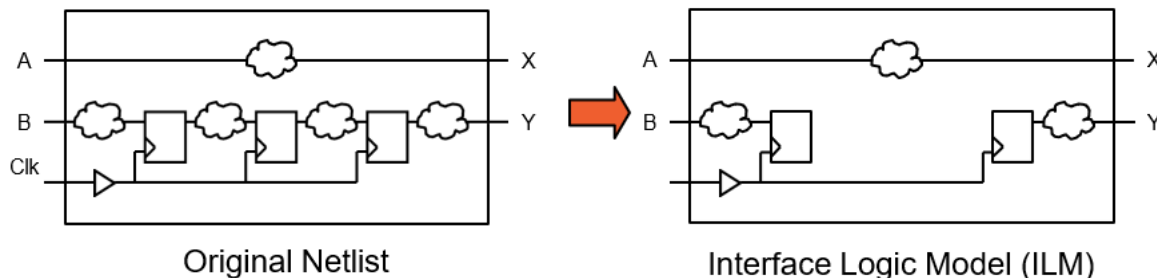


HIERARCHICAL DESIGN – TIME BUDGETING

- Chip level constraints must be mapped correctly to block level constraints as I/O constraints

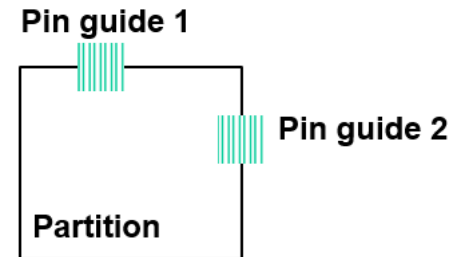
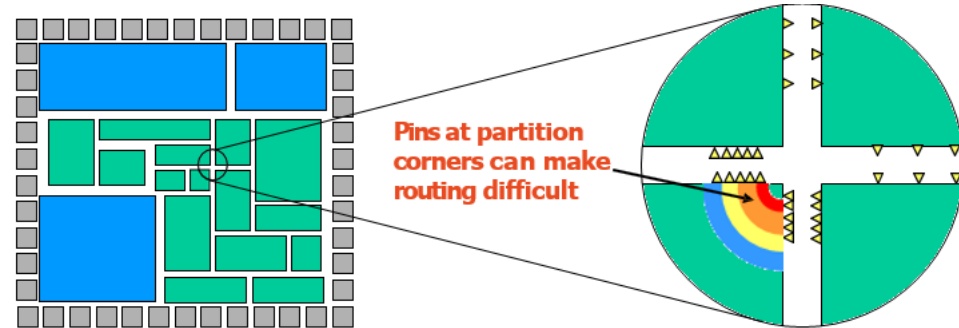


- Interface Logic Models (ILMs) help simplify and speed-up design



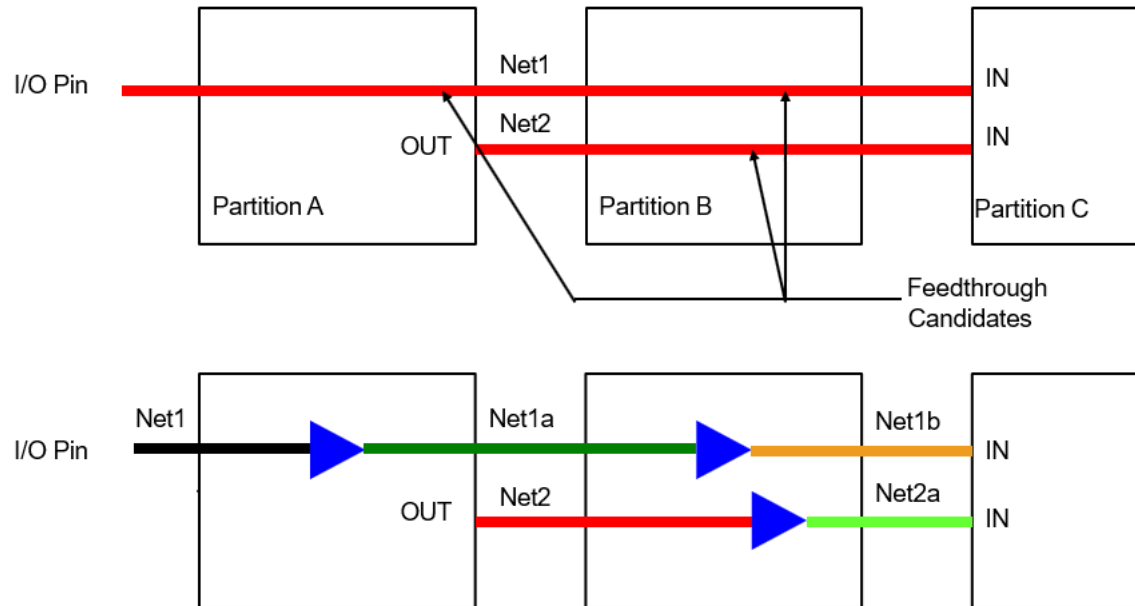
HIERARCHICAL DESIGN – PIN ASSIGNMENT

- Pin constraints include parameters, such as:
 - Layers, spacing, size, overlap
 - Net groups, pin guides
- Pins can be assigned:
 - Placement-based (flightlines)
 - Route-based (trial route, boundary crossings).
- Pin guides
 - Can be used to influence automatic pin placement of particular net groups



HIERARCHICAL DESIGN – FEEDTHROUGH

- For channel-less designs or designs with limited channel resources



Power Planning

POWER PLANNING

Dynamic Power



Static Power
(Leakage Power)

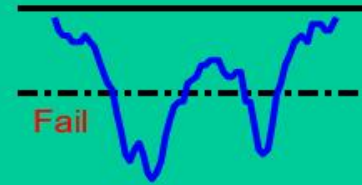


Floorplan
+
Design of the grid

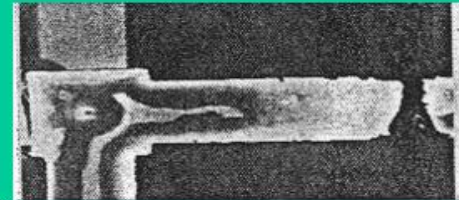
Average or
Instantaneous
Power problem

Power density
problem in the
Long run

IR-Drop /
Voltage Droop

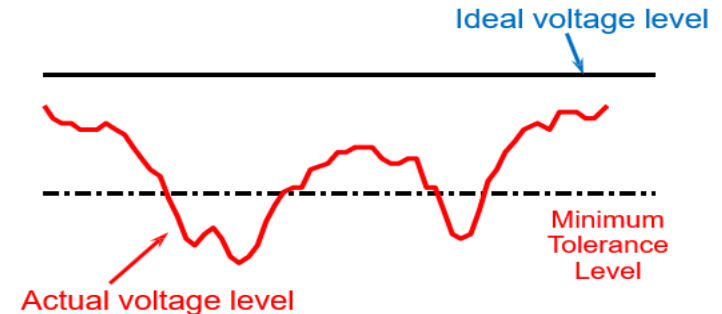
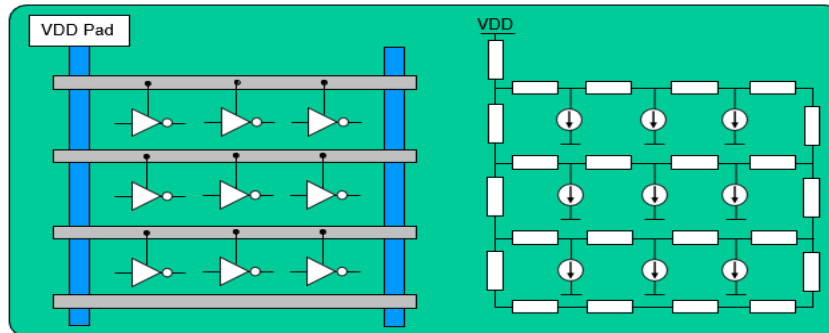
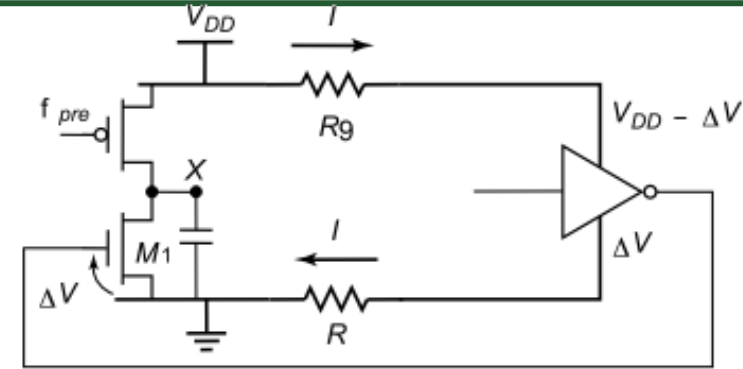


Electromigration
(EM)



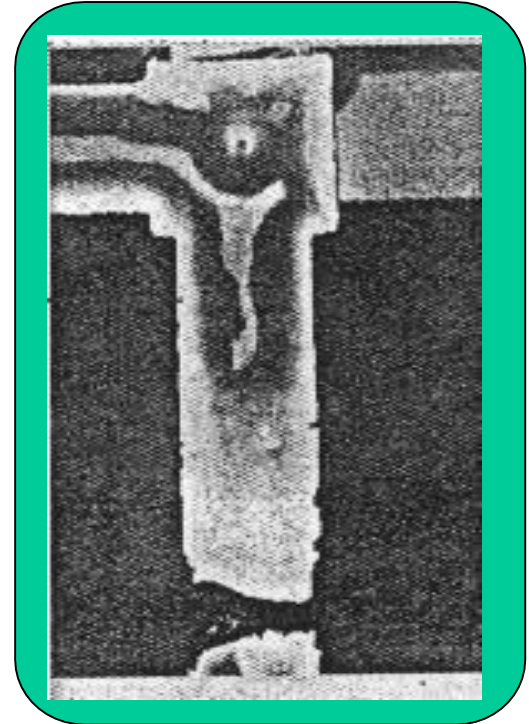
IR DROP

- The drop in supply voltage over the length of the supply line
 - A resistance matrix of the power grid is constructed
 - The average current of each gate is considered
 - The matrix is solved for the current at each node, to determine the IR-drop.



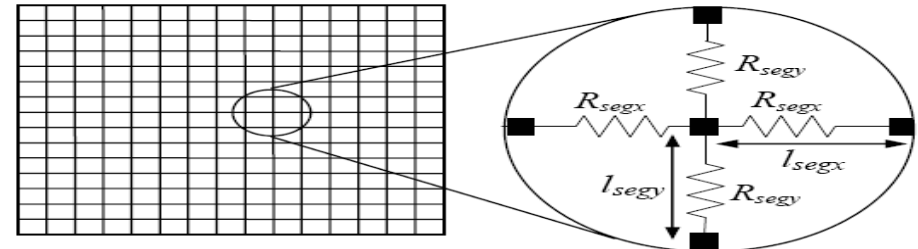
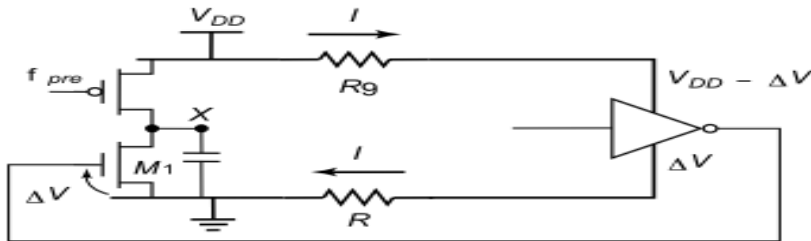
ELECTROMIGRATION (EM)

- Electromigration refers to the gradual displacement of the metal atoms of a conductor as a result of the current flowing through that conductor.
 - Transfer of electron momentum
- Can result in catastrophic failure do to either
 - **Open** : void on a single wire
 - **Short** : bridging between to wires
- Even without open or short, EM can cause performance degradation
 - Increase/decrease in wire RC



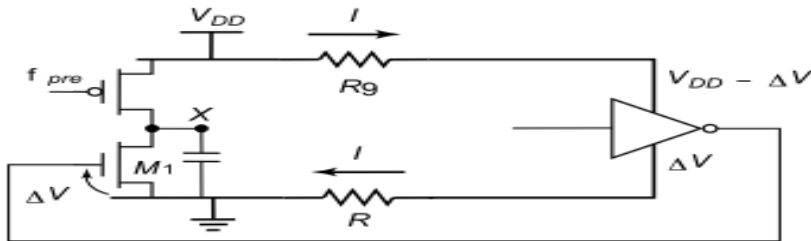
POWER DISTRIBUTION

- Power Distribution Network functions
 - Carry **current** from pads to transistors on chip
 - Maintain stable **voltage** with low noise
 - Provide average and peak **power** demands
 - Provide current **return paths** for signals
 - Avoid **electromigration** & self-heating **wearout**
 - Consume little chip **area** and **wire**
 - Easy to lay out



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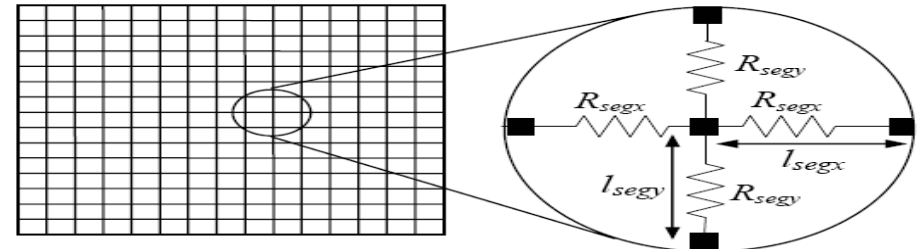
More (Wider) Power Lines:

- Less Static (IR) drop
- Less Dynamic (dI/dt) drop
- Less Electromigration

BUT

More (Wider) Power Lines:

- Fewer (signal) routing resources (i.e., higher congestion)



POWER DISTRIBUTION CHALLENGE

- Assume we have a 1mm long power rail in M1.
 - Square resistance is given to be 0.1 ohm/square
 - If we make a 100nm wide rail, what is the **resistance** of the wire?

$$R = R_{\square} L/W = 0.1 \frac{\Omega}{\square} \cdot \frac{10^{-3} m}{100 \cdot 10^{-9} m} = 1000 \Omega$$

- Now, given a max current of 1mA/1um, due to **Electromigration**, what is the **IR drop** when conducting such a current through this wire?

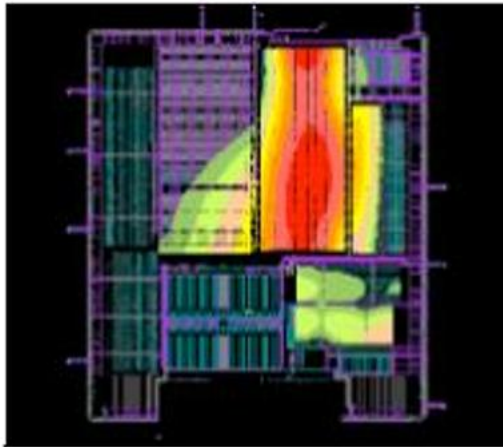
$$I_{\max} = \frac{1 \text{mA}}{1 \mu\text{m}} \cdot 100 \text{nm} = 0.1 \text{mA}$$

$$IR_{\text{drop}} = I_{\max} \cdot R_{\text{wire}} = 10^{-4} \cdot 10^3 = 100 \text{mV}$$

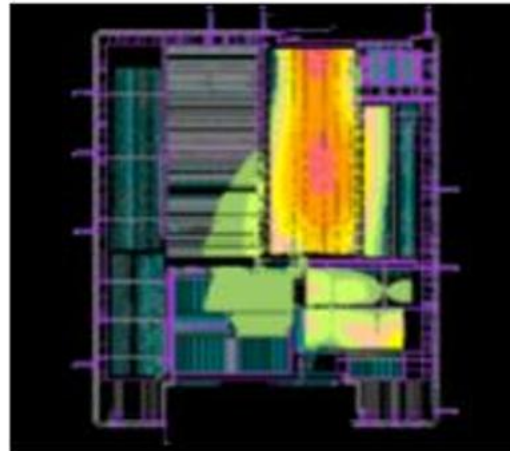
- So what do we do?
 - Make the power rails as wide and as thick as possible!

HOT SPOTS

- We generally map the **IR drop** of a chip using a color map to highlight “hot spots”, where the **IR drop** is bad.



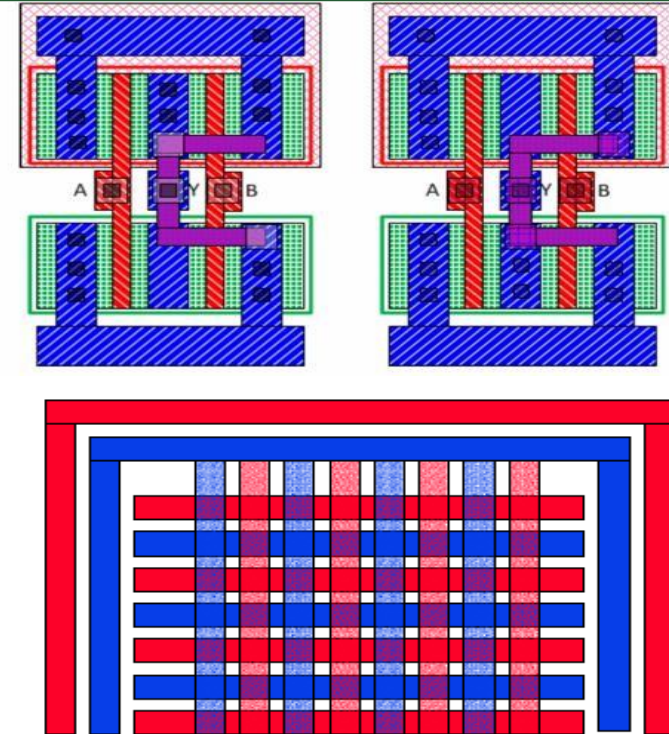
Initial IR Drop Mapping



Source:
Cadence

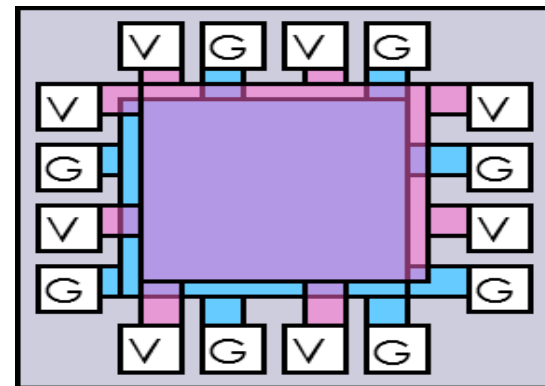
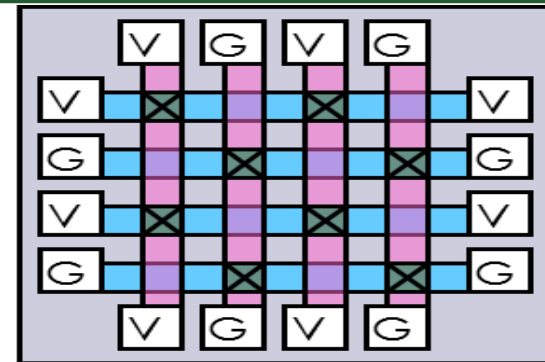
POWER AND GROUND ROUTING

- Each standard cell or macro has power and ground signals, i.e., **VDD** (power) and **GND** (ground)
 - They need to be connected as well
- Power/Ground **mesh** will allow multiple paths from P/G sources to destinations
 - Less series **resistance**
 - Hierarchical power and ground **meshes** from upper metal layers to lower metal layers
 - **Multiple vias** between layers
- You can imagine that they are HUGE NETWORKS!
 - In general, P/G routings are pretty regular
 - P/G routing resources are usually reserved



STANDARD APPROACHES TO POWER ROUTING

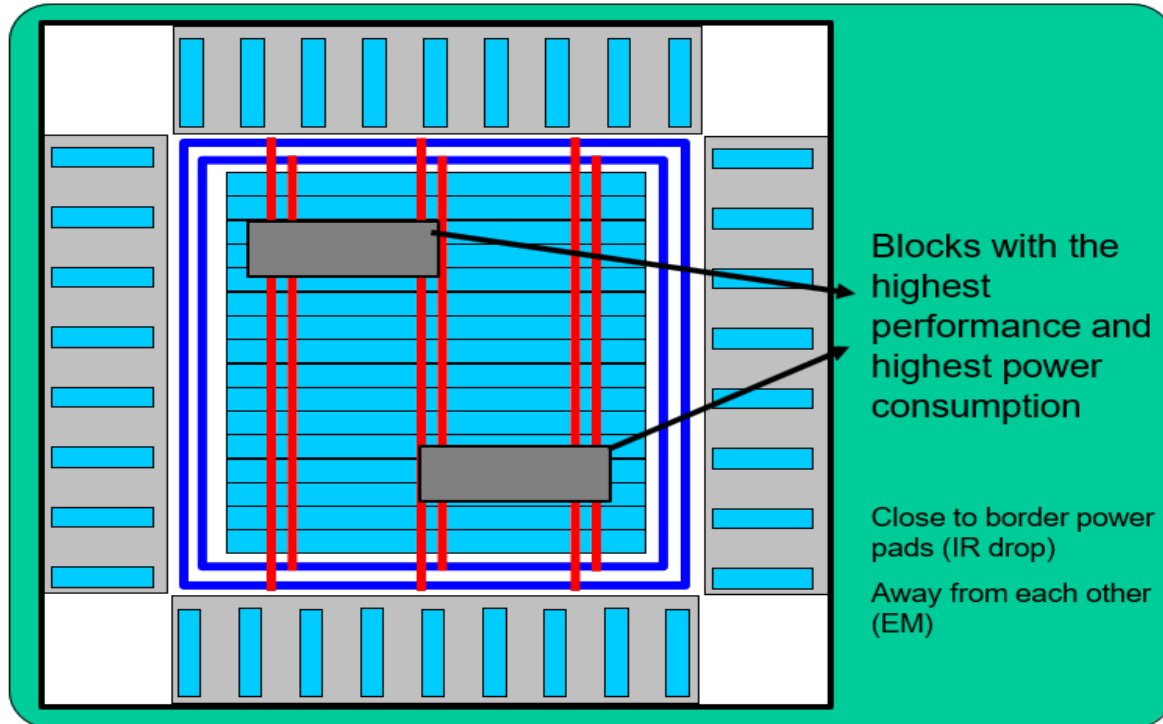
- Power grid
 - Interconnected vertical and horizontal power bars.
 - Common on most high-performance designs.
 - Often well over half of total metal on upper thicker layers used for VDD/GND.
- Dedicated VDD/GND planes.
 - Very expensive.
 - Only used on Alpha 21264, Dropped on subsequent Alphas.
 - Simplified circuit analysis.
- Some thoughts/trends:
 - P/G I/O pad co-optimization with classic physical design
 - Decoupling capacitors to reduce P/G related voltage drop
 - Multiple voltage/frequency islands make the P/G problem and clock distributions more challenging.



POWER GRID CREATION

- Tradeoff IR drop and EM versus routing resources
 - Require power budget
 - Initial power estimation
 - Average current, max current density
- Need to determine
 - General grid structure (gating or multi-voltage?)
 - Number and location of power pads (per voltage)
 - Metal layers to be used
 - Width and spacing of straps
 - Via stacks versus available routing tracks
 - Rings / no rings
 - Hierarchical block shielding
- Run initial power network analysis to confirm design

POWER GRID CREATION – MACRO PLACEMENT



CLOCK PLANNING

- Clocking scheme is planned at this stage
- We will talk about the schemes in the upcoming lectures.

Thank you!